



TSMC-00-068BD

April 5, 2004

To: Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

Fr: George O. Saile, Reg. No. 19,572
28 Davis Avenue
Poughkeepsie, N.Y. 12603

Subject:

Serial No. 10/790,919 03/02/04

Ta-Lee Yu

BIPOLAR ESD PROTECTION STRUCTURE

INFORMATION DISCLOSURE STATEMENT

Enclosed is Form PTO-1449, Information Disclosure Citation
In An Application.

The following Patents and/or Publications are submitted to
comply with the duty of disclosure under CFR 1.97-1.99 and
37 CFR 1.56.

CERTIFICATE OF MAILING

I hereby certify that this correspondence is being
deposited with the United States Postal Service as first class
mail in an envelope addressed to: Commissioner for Patents,
P.O. Box 1450, Alexandria, VA 22313-1450, on April 12, 2004.

Stephen B. Ackerman, Reg.# 37761

Signature/Date SB Ackerman 4/12/04

The report by J. Chen et al., "Design and Layout of a High ESD Performance NPN Structure for Submicron BiCMOS/Bipolar Circuits," IEEE Journal 1996, 0-7803-2753-5/96, pp. 227-232, describes how ESD efficiency is typically measured by dividing the ESD "threshold" voltage by the area of the ESD protection device and discusses various ESD protection device layouts.

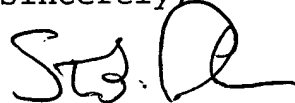
U.S. Patent 5,850,095 to Chen et al., "ESD Protection Circuit Using Zener Diode and Interdigitated NPN Transistor," describes an electrostatic discharge (ESD) protection circuit.

U.S. Patent 5,341,005 to Canclini, "Structure for Protecting an Integrated Circuit from Electrostatic Discharges," discloses different structures for ESD protection.

U.S. Patent 5,528,189 to Khatibzadeh, "Noise Performance of Amplifiers," discloses an amplifier with ESD protection with emitter finger layouts.

U.S. Patent 5,301,084 to Miller, "Electrostatic Discharge Protection for CMOS Integrated Circuits," discusses ESD protection circuits.

Sincerely,

A handwritten signature in black ink, appearing to read "S.B. Ackerman", written over a horizontal line.

Stephen B. Ackerman,
Reg. No. 37761

Lysine

10/790,919

Ta Lee Yu

03/02/04

Group 11 Unit

(Use several sheets if necessary)

U. S. PATENT DOCUMENTS

A circular ink stamp from the Office of the Patent & Trademark Examiner. The text "OIPET" is curved along the top inner edge, and "APR 15 2004" is stamped in the center. The words "OFFICE OF THE PATENT & TRADEMARK EXAMINER" are curved along the bottom inner edge. The number "150" is visible in the top right corner of the stamp area.

FOREIGN PATENT DOCUMENTS

[illegible]

OTHER DOCUMENTS (Including Author, Title, Date, Portion or Pages, Etc.)

- J. Chen et al., "Design and Layout of a High ESD Performance NPN Structure for Submicron BiCMOS/Bipolar Circuits", IEEE Jnl 1996, 0-7803-2753-5/96, pp. 227-232.

DATE COMPLETED

EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP § 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to the applicant.